Se	arcn	NOTE	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/630,572	YOSHIDA, HIROKI	
Examiner	Art Unit	
Charlotte M. Baker	2625	

SEARCHED					
Subclass	Date	Examiner			
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Consulted Primary Examiner Wenpeng Chen	7/17/2006	СМВ	
Consulted Supervisory Examiner Kimberly Williams	7/18/2006	СМВ	